

10-14-2005

Sheet 1 of 1

OI OCT 14 2005 (37 CFR §1.98(b)) <small>PATENT &amp; TRADEMARK OFFICE</small>	Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 10559-887001	Application No. 10/649,354
	Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Florence Eschbach et al.		
			Filing Date August 26, 2003	Group Art Unit 1773	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
M	AJ	0 942 325	09/1999	EPO			
	AK						
	AL						
	AM						
	AN						

Other Documents (include Author, Title, Date, and Place of Publication)							
Examiner Initial	Desig. ID	Document					
M	AO	Chen, et al., "Pellicle-Induced Reticle Distortion: An Experimental Investigation", <i>Proc. of SPIE - The Int'l Soc. for Optical Engineering</i> , Vol. 3546, pp. 167-172 (1998).					
	AP	Cotte, et al., "Effects of Soft Pellicle Frame Curvature and Mounting Process on Pellicle-Induced Distortions in Advanced Photomasks", <i>Proc. of SPIE - The Int'l Soc. for Optical Engineering</i> , Vol. 5040, pp. 1044-1054 (2003).					
	AQ	Cotte, et al., "Experimental and Numerical Studies of the Effects of Materials and Attachment Conditions on Pellicle-Induced Distortions in Advanced Photomasks", <i>Proc. of SPIE - The Int'l Soc. for Optical Engineering</i> , Vol. 4754, pp. 579-588 (2002).					
Z	AR	Cotte, et al., "Numerical and Experimental Studies of Pellicle-Induced Photomask Distortions", <i>Proc. of SPIE - The Int'l Soc. for Optical Engineering</i> , Vol. 4562, pp. 641-651 (2002).					

Examiner Signature	Date Considered
	12/6/05
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	